

Specification	AXIOM45	Issue: 01	Date: 2005-07-15
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Oscillator type : OCXO High stability, Sinewave Output

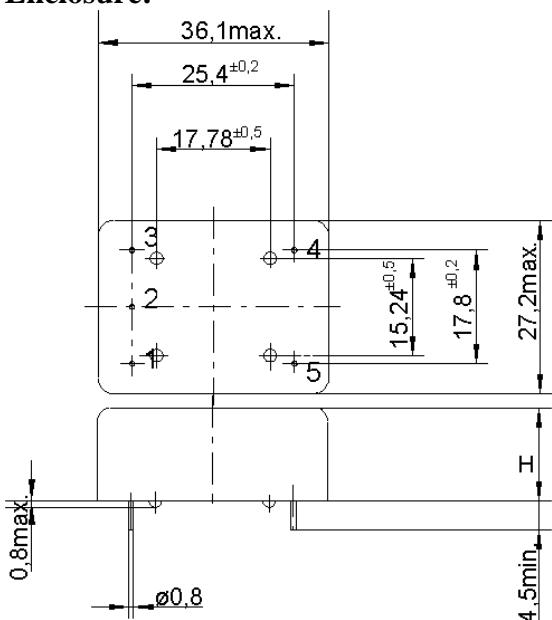
Parameter	min.	typ.	max.	Unit	Condition
Frequency range	5		120	MHz	
Standard frequencies		10 / 16.384 / 20		MHz	
Frequency stability				ppm	
Initial tolerance		± 500		ppb	@+25°C, V _C = 2.5V
vs. temperature in operating temperature range (steady state)			± 100 ± 50 ± 25 ± 10	ppb ppb ppb ppb	Option II = "100" Option II = "50" Option II = "25" Option II = "10"
operating temperature range	-20		+70	°C	
vs. supply voltage variation			± 2	ppb	V _S ± 5%
vs. load change			± 2	ppb	
long term stability (aging) per year after 30 days operation			± 200 ± 100	ppb/year ppb/year	Option II = "100" Option II = "50", "25" and "10"
Frequency adjustment range					
Electronic Frequency Control (EFC) range	± 5 ± 1			ppm ppm	Option II = "100" Option II = "50", "25" and "10"
EFC voltage V _C	0.25		4.75	V	
EFC slope ($\Delta f / \Delta V_C$)		positive			
EFC input impedance	100			kΩ	
RF output					
Signal waveform		Sinus			
Load		50		Ohm	
Output amplitude	+3			dBm	
Harmonics attenuation	30			dBc	
Warm-up time @25°C			5	min	$\Delta f_{final}/f_0 < \pm 0.1$ ppm
Phase noise @ 10.0 MHz Option II = „50“		-100 -130 -145 -155		dBc dBc dBc dBc	10 Hz 100 Hz 1000 Hz 10000 Hz
Supply voltage V_S	4.75 11.4	5.0 12	5.25 12.6	V V	Option I = "50" Option I = "12"
Current consumption (steady state) @ +25°C			200 80	mA mA	Option I = "50" Option I = "12"
Current consumption (warm-up)			500 200	mA mA	
Operable temperature range	-30		+75	°C	
Storage temperature range	-40		+85	°C	
Enclosure (see drawing) (Note 2)		36.1x27.2x19.4 max.		mm	IEC 60679-3 CO 08
Weight			30	gram	
Packing		Bulk			
ESD Sensitivity	1500			V	HBM IEC 61000-4-2

Notes:

1. Terminology and test conditions are according to IEC standard IEC60679-1, unless otherwise stated
2. Lower package height (15 mm, 13 mm) on request

Ordering Code:

Model (Specification)	Option I	Option II	Frequency [MHz]
AXIOM45	50	100	10.000

Enclosure:

Pin connections

Pin #	Symbol	Function
1	V _C	Control Voltage (EFC)
2	N.C.	No Connection
3	V _S	Supply Voltage
4	RF OUT	RF Output
5	GND	Ground

Environmental conditions

Test	IEC 60068 Part ...	IEC 60679-1 clause ...	Test conditions
Visual inspection, dimensions		4.3	Enclosure styles as in IEC 60679-3 or 61837, if applicable
Sealing tests (if applicable)	2-17	4.6.2	Gross leak: Test Qc, Fine leak: Test Qk
Solderability Resistance to soldering heat	2-20 2-58	4.6.3	Test Ta (235 ± 5)°C Method 1 Test Tb Method 1A, 5s
Shock*	2-27	4.6.8	Test Ea, 3 x per axes 100g, 6 ms half-sine pulse
Bump*	2-29	4.6.6	Test Eb, 4000 bumps per Axes, 40g, 6 ms
Free fall*	2-32	4.6.9	Test Ed procedure 1, 2 drops from 1m height
Vibration, sinusoidal*	2-6	4.6.7	Test Fc, 30 min per axes, 10 Hz - 55 Hz 0.75mm; 55 Hz - 2 kHz, 10g
Rapid change of temperature	2-14	4.6.5	Test Na, 10 cycles at extremes of operating temperature range
Dry heat	2-2	4.6.14	Test Ba, 16 h at upper temperature indicated by climatic category
Damp heat, cyclic*	2-30	4.6.15	Test Db variant 1 severity b), 55°C/95% r.H., 6 cycles
Cold	2-1	4.6.16	Test Aa, 2 h at lower temperature indicated by climatic category
Climatic sequence*	1-7	4.6.17	Sequence of 4.6.14, 4.6.15 (1 st cycle), 4.6.16, 4.6.15 (5 cycles)
Damp heat, steady state*	2-3	4.6.18	Test Ca, 56 days
Endurance tests - ageing - extended aging		4.7.1 4.7.2	30 days @ 85°C, OCXO @25°C 1000h, 2000h, 8000h @85°C